Notice	of References	Cited
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Application/Control No. Applicant(s)/Patent		nt Under	
	10/566,531	Reexamination FECHTEL ET AL.	
	Examiner	Art Unit	
	DAVID HUANG	2611	Page 1 of 1

U.S. PATENT DOCUMENTS

	Old Filter Decometry				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,122,703 A	09-2000	Nasserbakht, Mitra	711/5
*	В	US-2003/0084079 A1	05-2003	Awad et al.	708/322
*	С	US-2003/0128751 A1	07-2003	Vandenameele-Lepla, Patrick	375/229
*	D	US-6,674,820 B1	01-2004	Hui et al.	375/346
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	T	US-			
	J	US-			
	к	US-			
	L	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

NON-FATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	v				
	w				
	x				

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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